

Short portrait of the testing lab nanoAnalytics

nanoAnalytics was founded 1999 as independent testing lab. We are specialised on the chemical and structural characterisation of surfaces and interfaces in the micro and nanometer scale.



What may we do for you?

Our interdisciplinary team offers long standing experience on the field of surface analytics. This experience and modern analytical techniques allow us to analyse very diverting samples for you.

Confidentiality

The confidential treatment of your data and materials is self-evident for us. We can additionally sign a Confidentiality Agreement if you want to.

We set a high value on quality and competence!

- Our practice was evaluated from an independent side:
We are accredited as testing lab according to DIN EN ISO/IEC 17025.
- Our quality management equates to ISO 9001.
- The application processing is carried out in tight coordination with you.
- You get the results of the analysis within six working days most.

Analytical methods by nanoAnalytics

The following list gives an overview about the analytical and preparation methods used by us. These methods are available at Münster site directly or provided by partners from long lasting cooperations.



We use following methods :

- Scanning electron microscopy and energy dispersive x-ray microanalysis (SEM / EDS)
- Photo electron spectrometry (ESCA / XPS)
- Secondary ion mass spectrometry (TOF-SIMS)
- Optical interferometer
- Scanning force microscopy (SFM)
- Optical microscopy (fluorescence, polarisation, DIC)
- Contact angle measurements

Additional we offer the following methods to you:

- Infrared spectroscopy and microscopy (FTIR / ATR)
- Transmission electron microscopy (TEM)
- Nano- und Microindentation
- Glow Discharge Optical Emission Spectroscopy (GDOS)
- Secondary Neutral Mass Spectrometry (SNMS)
- Micro computer tomography

Special methods of preparation:

- Cryo fracture
- Ultra microtome (also under cryo conditions)
- Preparation of cross-sections and targeting polish
- Preparation by Focussed Ion Beam (FIB)